Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type ($L^2-\pi$ -MOSV)

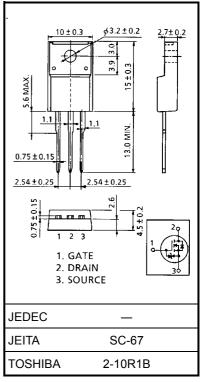
2SK2391

Chopper Regulator, DC–DC Converter and Motor Drive Applications

- 4 V gate drive
- Low drain-source ON resistance $: R_{DS}(ON) = 66 \text{ m}\Omega \text{ (typ.)}$
- High forward transfer admittance $|Y_{fs}| = 16 \text{ S (typ.)}$
- Low leakage current $: I_{DSS} = 100 \ \mu A \ (max) \ (V_{DS} = 100 \ V)$
- Enhancement-mode : $V_{th} = 0.8 \sim 2.0 \text{ V} (V_{DS} = 10 \text{ V}, \text{ Ip} = 1 \text{ mA})$

Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit	
Drain-source voltage		V _{DSS}	100	V	
Drain-gate voltage (R	_{GS} = 20 kΩ)	V _{DGR}	100	V	
Gate-source voltage		V _{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	20	А	
	Pulse (Note 1)	I _{DP}	80	А	
Drain power dissipatio	n (Tc = 25°C)	PD	35	W	
Single pulse avalanche	e energy (Note 2)	E _{AS}	208	mJ	
Avalanche current		I _{AR}	20	А	
Repetitive avalanche e	energy (Note 3)	E _{AR}	3.5	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature r	ange	T _{stg}	-55~150	°C	



Weight: 1.9 g (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	3.57	°C / W
Thermal resistance, channel to ambient	R _{th (ch−a)}	62.5	°C / W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: V_DD = 25 V, T_ch = 25°C (initial), L = 840 $\mu H, R_G$ = 25 Ω, I_{AR} = 20 A

Note 3: Repetitive rating; Pulse width limited by maximum channel temperature.

This transistor is an electrostatic sensitive device. Please handle with caution.

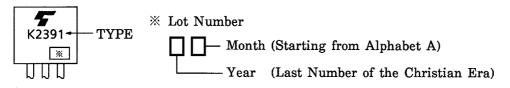
Electrical Characteristics (Ta = 25°C)

Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μA
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V	_	_	100	μA
Drain-source br	eakdown voltage	V _(BR) DSS	I _D = 10 mA, V _{GS} = 0 V	100	-	_	V
Gate threshold v	voltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V
Drain-source ON resistance		R _{DS (ON)}	V _{GS} = 4 V, I _D = 10 A		0.09	0.13	Ω
			V _{GS} = 10 V, I _D = 10 A	_	0.066	0.085	
Forward transfe	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 10 A	8	16	—	S
Input capacitance	ce	C _{iss}			1100	—	
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	180	_	pF
Output capacitance		C _{oss}		_	400	_	
Switching time	Rise time	tr	$V_{GS} \stackrel{10 \text{ V}}{}_{0 \text{ V}} \int I_{D} = 10 \text{ A}$ $V_{OUT} \stackrel{V_{OUT}}{}_{C} \stackrel{V_{OU}}{}_{C} \stackrel{V}{}_{C} \stackrel{V_{OU}}{}_{C} \stackrel{V_{OU}}{}_{C} \stackrel{V}{$	_	20	_	ns
	Turn-on time	t _{on}		_	30	—	
	Fall time	t _f		_	50	—	
	Turn-off time	t _{off}	Duty ≤ 1 %, t _w = 10 μ s	_	140	_	
Total gate charge (Gate-source plus gate-drain)		Qg		_	50	_	
Gate-source charge		Q _{gs}	V _{DD} ≈ 80 V, V _{GS} = 10 V, I _D = 27 A	—	34	—	nC
Gate-drain ("miller") charge		Q _{gd}			16	_	

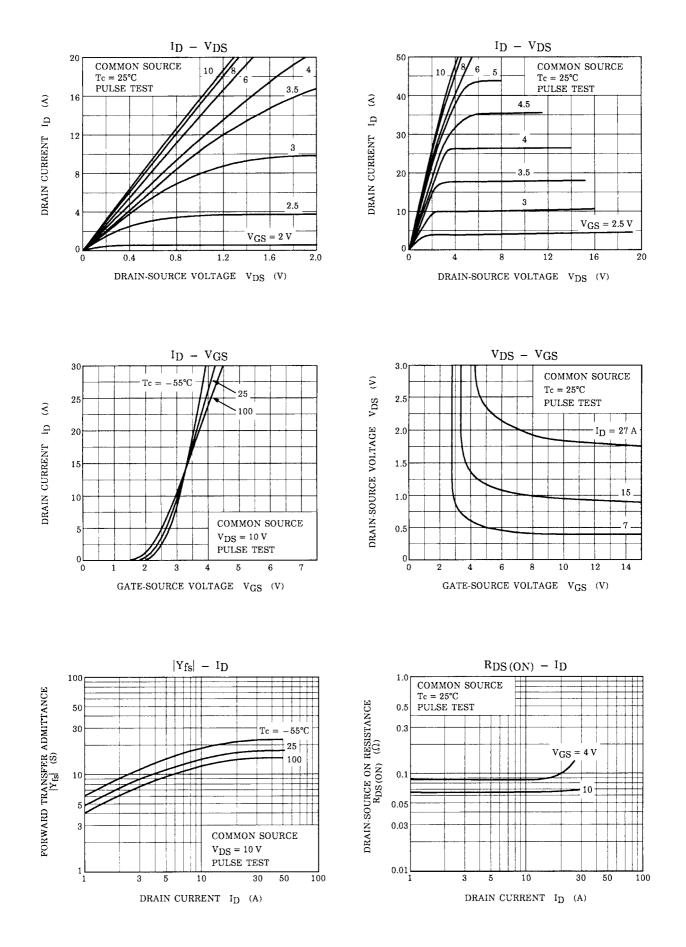
Source–Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	—	_	_	20	А
Pulse drain reverse current (Note 1)	I _{DRP}	—	_	_	80	А
Forward voltage (diode)	V _{DSF}	I _{DR} = 20 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 20 A, V _{GS} = 0 V, dI _{DR} / dt = 50 A / μs	_	155	_	ns
Reverse recovery charge	Q _{rr}	$\mu_{\text{DR}} = 20$ A, $\nu_{\text{GS}} = 0$ V, $\mu_{\text{DR}} = 50$ A / μ_{S}	_	0.31	_	μC

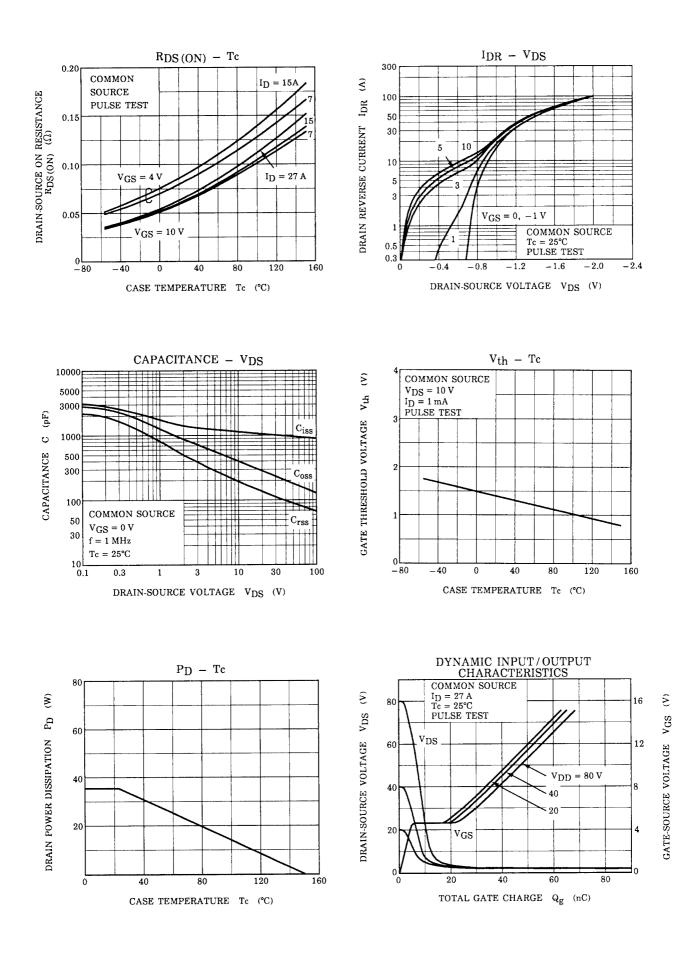
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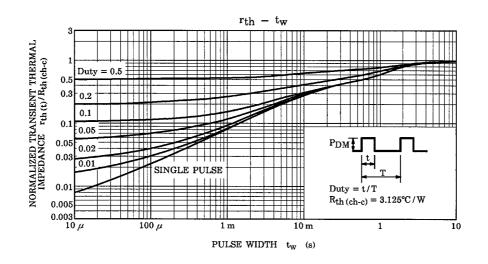


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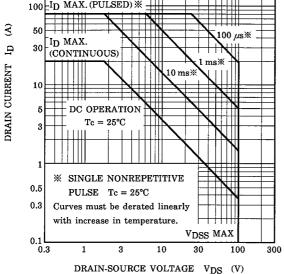


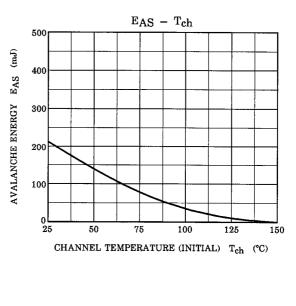
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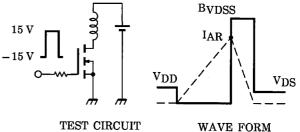




SAFE OPERATING AREA







$$\begin{array}{l} \mathrm{R_{G}=25\ \Omega} \\ \mathrm{V_{DD}=25\ V,\ L=840\ \mu H} \end{array} \qquad \mathrm{EAS}=\frac{1}{2}\cdot\mathrm{L}\cdot\mathrm{I}^{2}\cdot\left(\frac{\mathrm{BVDSS}}{\mathrm{BVDSS}-\mathrm{VDD}}\right) \end{array}$$

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